

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. <b>455610-2590.3</b>		SERIAL NO. <b>10/673,713</b>	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <b>Martin MILLER et al.</b>			
FILING DATE <b>September 29, 2003</b>				GROUP <b>2186</b>			

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EXAMINER INITIAL	CLASS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
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/EC/	AB	5,726,607	03/10/98	Brede et al			
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/EC/	AD	5,900,755	05/04/99	Toeppen et al			
/EC/	AE	6,215,363	04/10/01	Conta et al			
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							YES	NO
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/EC/	AO	JP5196641	08/06/93	Japan			Abstract	
/EC/	AP	JP5264595	10/12/93	Japan			Abstract	
/EC/	AQ	JP8220144	06/22/99	Japan			Abstract	
/EC/	AR	JP9005362	01/10/97	Japan			Abstract	
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/EC/	AT	JP11098876	04/09/99	Japan			Abstract	
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/EC/	BA		HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
/EC/	BB		Infinium DCA, Agilent Technologies, March 7, 2002
	BC		<del>Communication waveform measurements, Hewlett Packard, June 26, 1990</del>

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APPLICANT

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/EC/	BS		Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000
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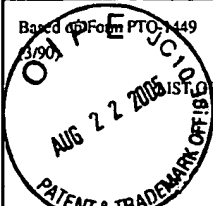
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	FILING DATE <b>September 29, 2003</b>	GROUP <b>2133</b>

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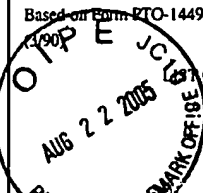
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/EC/	AS		Adam Healey, "Fast Ethernet Consortium Notebook", 1996-1997 14 pps.
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							YES	NO
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Sheet 1 of 1

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	APPLICANT Martin Thomas MILLER et al.	
	FILING DATE September 29, 2003	GROUP 2133

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	AG						
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	AJ						
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							YES	NO
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	AM							
	AN							
	AO							
	AP							

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